

# CE1F3P

# on-chip resistor NPN silicon epitaxial transistor For mid-speed switching

The CE1F3P is a transistor of on-chip high hFE resistor incorporating dumper diode in collector to emitter and zener diode in collector to base as protect elements. This transistor is ideal for actuator drives of OA equipments and electric equipments.

#### **FEATURES**

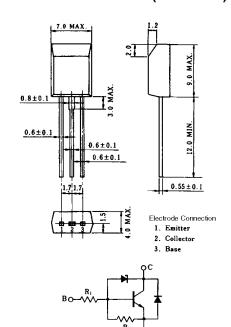
- On-chip zener diode for surge voltage absorption
- On-chip bias resistor: R1 = 2.2 k $\Omega$ , R2 = 10 k $\Omega$
- Low power consumption during driving:
   Vol = 0.12 V @VI = 5.0 V, Ic = 0.5 A
- On-chip dumper diode for reverse cable

#### ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

Parameter	Symbol	Ratings	Unit
Collector to base voltage	Vсво	60±10	V
Collector to emitter voltage	VCEO	60±10	V
Emitter to base voltage	VEBO	15	V
Collector current (DC)	Ic(DC)	±2.0	Α
Collector current (Pulse)	Ic(pulse) *	±3.0	Α
Base current (DC)	I <sub>B(DC)</sub>	0.03	Α
Total power dissipation	Рт	1.0	W
Junction temperature	Tj	150	°C
Storage temperature	T <sub>stg</sub>	-55 to +150	°C

\* PW≤10 ms, duty cycle≤50 %

## PACKAGE DRAWING (UNIT: mm)



#### **ELECTRICAL CHARACTERISTICS (Ta = 25°C)**

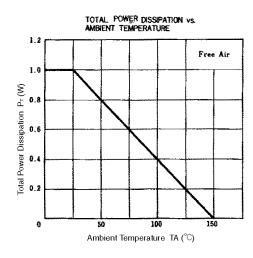
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Colletor to emitter voltage	VCEO(SUS)	Ic = 2.0 A, Iв = 5.0 Ma, L = 6.0 mH	50	60		V
Collector cutoff current	Ісво	V <sub>CB</sub> = 40 V, I <sub>E</sub> = 0			100	nA
DC current gain	h <sub>FE1</sub> **	Vce = 5.0 V, Ic = 0.2 A	700	1200		_
DC current gain	hFE2 **	Vce = 5.0 V, Ic = 1.0 A	1000	1600	3000	_
DC current gain	h <sub>FE3</sub> **	Vce = 5.0 V, Ic = 2.0 A	500	1200		-
Low level output voltage	<b>V</b> ol **	V <sub>I</sub> = 5.0 V, I <sub>C</sub> = 0.5 A		0.12	0.3	V
Low level input voltage	VIL **	$V_{CE} = 12 \text{ V}, \text{ Ic} = 100 \ \mu\text{A}$		0.5	0.4	٧
Input resistance 1	R <sub>1</sub>		1.54	2.2	2.86	kΩ
Input resistance 2	R <sub>2</sub>		7.0	10.0	13.0	kΩ
Turn-on time	ton	Ic = 1.0 A		0.4		μs
Storage time	tstg	Іві = –Ів2 = 10 mA		1.4		μs
Fall time	tf	$Vcc = 20 \text{ V}, \text{ RL} = 20 \Omega$		0.5		μs

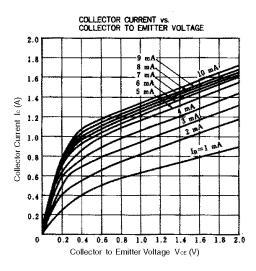
<sup>\*\*</sup> Pulse test PW  $\leq$  350  $\mu$ s, duty cycle  $\leq$  2 %

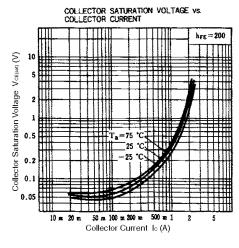
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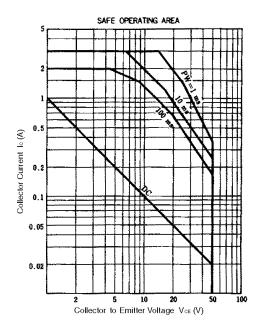


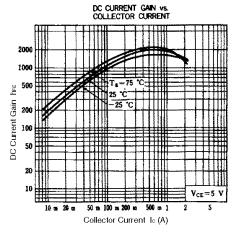
## TYPICAL CHARACTERISTICS (Ta = 25°C)

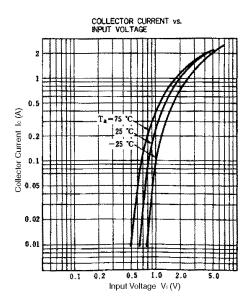


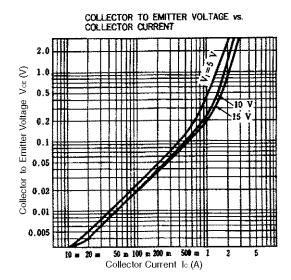


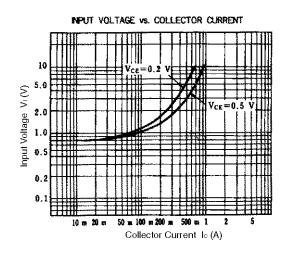












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